

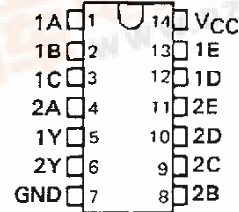
SN54S260, SN74S260 DUAL 5-INPUT POSITIVE-NOR GATES

SDLS208

DECEMBER 1983 — REVISED MARCH 1988

- Package Options Include Ceramic Chip Carriers and Flat Packages in Addition to Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

SN54S260 . . . J OR W PACKAGE
SN74S260 . . . D OR N PACKAGE
(TOP VIEW)

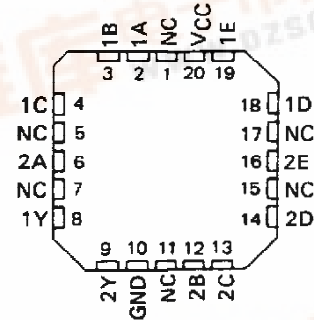


description

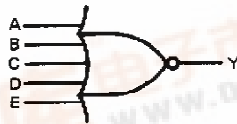
These devices contain two independent 5-input positive -NOR gates. They perform the Boolean function $Y = \overline{A + B + C + D + E}$ in positive logic.

The SN54S260 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74S260 is characterized for operation from 0°C to 70°C .

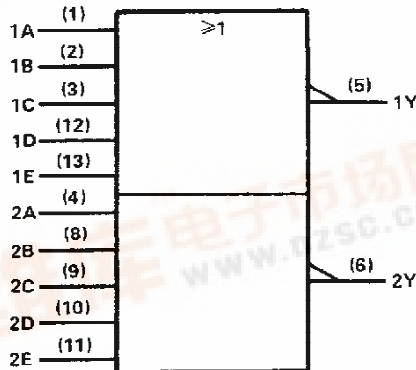
SN54S260 . . . FK PACKAGE
(TOP VIEW)



logic diagram (each gate)



logic symbol†



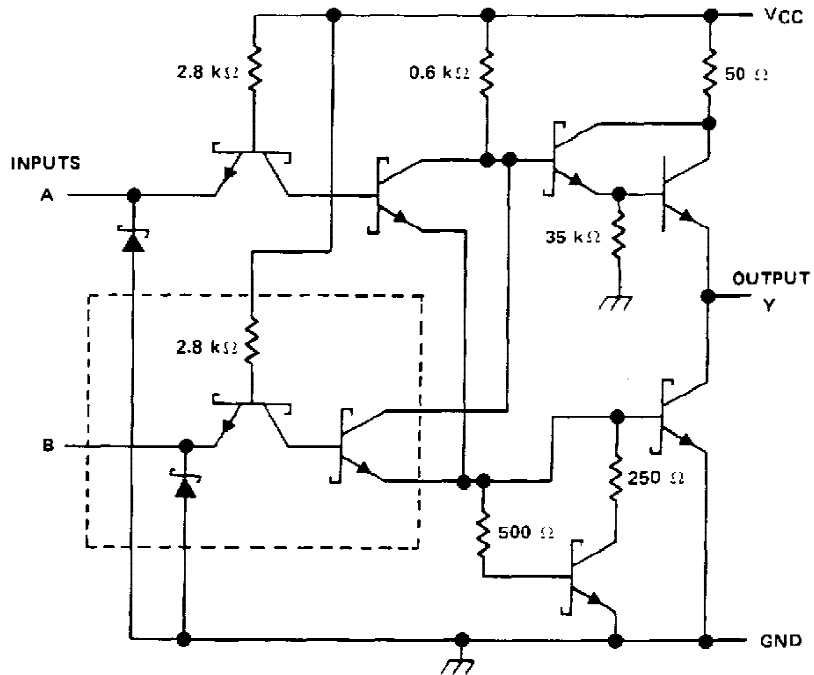
† This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

NC - No internal connection

SN54S260, SN74S260 DUAL 5-INPUT POSITIVE-NOR GATES

schematic (each gate)



Resistor values shown are nominal.
The portion of the schematic within the dashed-line is repeated for each additional input.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage	5.5 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

SN54S260, SN74S260 DUAL 5-INPUT POSITIVE-NOR GATES

recommended operating conditions

	SN54S260			SN74S260			UNIT
	MIN	TYP	MAX	MIN	TYP	MAX	
V_{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH} High-level input voltage	2			2			V
V_{IL} Low-level input voltage				0.8			V
I_{OH} High-level output current				-1			mA
I_{OL} Low-level output current				20			mA
T_A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN54S260			SN74S260			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V_{IK}	$V_{CC} = \text{MIN}$, $I_I = -18 \text{ mA}$	-1.2			-1.2			V
V_{OH}	$V_{CC} = \text{MIN}$, $V_{IL} = 0.8 \text{ V}$, $I_{OH} = -1 \text{ mA}$	2.5	3.4		2.7	3.4		V
V_{OL}	$V_{CC} = \text{MIN}$, $V_{IH} = 2 \text{ V}$, $I_{OL} = 20 \text{ mA}$	0.5			0.5			V
I_I	$V_{CC} = \text{MAX}$, $V_I = 5.5 \text{ V}$	1			1			mA
I_{IH}	$V_{CC} = \text{MAX}$, $V_{IH} = 2.7 \text{ V}$	50			50			µA
I_{IL}	$V_{CC} = \text{MAX}$, $V_{IL} = 0.5 \text{ V}$	-2			-2			mA
$I_{OS} §$	$V_{CC} = \text{MAX}$	-40		-100	-40		-100	mA
I_{CCH}	$V_{CC} = \text{MAX}$, $V_I = 0 \text{ V}$	17			17			mA
I_{CCL}	$V_{CC} = \text{MAX}$, See Note 2	26			26			mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ \text{C}$.

§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

NOTE 2: One input at 4.5 V, all others at GND.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ \text{C}$ (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
t_{PLH}	Any	Y	$R_L = 280 \Omega$,	$C_L = 15 \text{ pF}$	4	5.5		ns
t_{PHL}					4	6		ns

NOTE 3: See General Information Section for load circuits and voltage waveforms.

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